

Search Notes

Application/Control No.

10/616,696

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

SUGITA ET AL.

Art Unit

1745

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 429 | 12 | 7/11/2007 | DWY |
| 429 | 34 | 7/11/2007 | DWY |
| 429 | 38 | 7/11/2007 | DWY |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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| 429 | 12 | 7/11/2007 | DWY |
| 429 | 34 | 7/11/2007 | DWY |
| 429 | 38 | 7/11/2007 | DWY |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---------------------|-----------|------|
| EAST | 7/11/2007 | DWY |
| Inventorship Search | 7/11/2007 | DWY |
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